

**Search Notes**

Application/Control No.

10/643,599

Examiner

David Mis

Applicant(s)/Patent under  
Reexamination

HEINONEN ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
331	2, 16, 18, 25, 49	1/26/2005	DM
327	147-150		
332	127		
360	51		
375	376		
455	260		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR